

Form PTO 1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1748SERIAL NO.  
09/879,331LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT Garo J. Derderian

PRIORITY FILING DATE  
June 11, 2001GROUP  
2818

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>DL</i>	AA 09/652,532		Derderian (as amended 11/29/2001)	—	—	06/31/2000
	AB					
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## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation	
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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*Thane Thasyle*

DATE CONSIDERED

*08/06/02*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1745SERIAL NO.  
09/879,231

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LIST OF ART CITED BY APPLICANT  
(Use several offices if necessary)

APPLICANT Gero J. Derderian

PRIORITY FILING DATE  
June 11, 2001GROUP  
2818

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	2002/0064915A1	05/2002	Kitamura	—	—	—
TL	AB	2001/0023110A1	09/2001	Fukuzumi et al	—	—	—
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## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

TL	AP		A.W. Ott, et al., "Atomic layer controlled deposition of Al <sub>2</sub> O <sub>3</sub> films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pps. 128-136.
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02/04/03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1748		SERIAL NO. 09/879,331	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Caro J. Dunderman			
				PRIORITY FILING DATE June 11, 2001		GROUP 2015	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	2002/0064915A1	05/2002	Memoria	—	—	—
TL	AB	2001/0033110A1	09/2001	Polunov et al	—	—	—
	AC						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AM						
	AN						
	AO						
OTHER REFERENCES (Including Author, Title, Date, Paragraph, Page, Etc.)							
TL	AP			A.W. Qi, et al., "Atomic layer controlled deposition of Al <sub>2</sub> O <sub>3</sub> films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pp. 128-136.			
	AQ						
	AR						
EXAMINER <i>TL</i>				DATE CONSIDERED 2/04/03			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with new communication to applicant.							

EV182661663

		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1748		SERIAL NO. 02379,231		
				APPLICANT: Gero J. Dardarian				
				PRIORITY FILING DATE June 11, 2001		GROUP 2818		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)								
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
TL	AA	5,126,283	06/1992	Finnbowell et al	—	—	—	
I	AB	5,025,233	04/1997	Cabral, Jr. et al	—	—	—	
✓	AC	4,933,519	03/2002	Lee	—	—	—	
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER: <i>[Signature]</i>				DATE CONSIDERED: 05/04/03				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 600; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1489

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
M22-1748

SERIAL NO.  
09/879,231

APPLICANT  
Cero J. Dorderias

PRIORITY FILING DATE  
June 11, 2001

GROUP  
2818

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
12	AA 6,222,722	04/99	Puhzami et al	-	-	-
↓	AB 6,204,070	3/01	Kim	-	-	-
↓	AC 6,207,487	3/01	Kim et al	-	-	-
↓	AD 6,391,805	3/02	Kim et al	-	-	-
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FOREIGN PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
12	AM KR 2002002157A	01/2002	Korea	-	-		
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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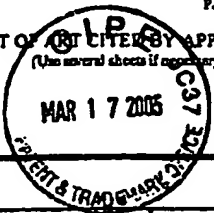
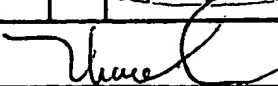
EXAMINER *Thawle* DATE CONSIDERED *10/14/03*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

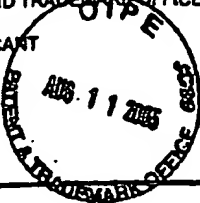
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Form PTO-140		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M372-1748		SERIAL NO. 09870231	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT <i>Caro J. Dardos</i>			
				FILING DATE June 11, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>TL</i>	AA	6,551,301	04/03	Smith et al	—	—	—
<i>TL</i>	AB	6,780,704	05/04	Radjenovic	—	—	—
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Publication Page, Etc.)							
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EXAMINER <i>Thurke</i>				DATE CONSIDERED <i>11/11/04</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with non commercial notice to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1748		SERIAL NO. 09/879,231	
LIST OF CITATIONS BY APPLICANT (Use several sheets if necessary) <div style="text-align: center;">  </div>				APPLICANT Garo J. Derderian			
				FILING DATE June 11, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
TL	AA 6,482,740	11/02	Soininen et al	—	—	—	
	AB 5,908,947	06/99	Vaartstra	—	—	—	
	AC 6,403,156	06/02	Jang	—	—	—	
	AD 6,746,930	06/04	Yang	—	—	—	
	AE 2002/0142488	10/02	Hong, Suk-Kyoung	—	—	—	
✓	AF 2005/0018381	07/03	McClure	—	—	—	
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AN						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
TL	AP		Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level," Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.				
TL	AQ		T. Suntola, Atomic Layer Epitaxy, Handbook of Crystal Growth, Vol. 3, 1994, pp. 603-663.				
TL	AR		Leskela and Ritala, ALD Precursor Chemistry: Evolution and Future Challenges, J. Phys. IV France 9 (1999), pages 837-852.				
TL	AS		Ritala et al, "Perfectly Conformal TiN and Al2O3 Films Deposited by Atomic Layer Deposition," Chemical Vapor Deposition, v. 5, No. 1, 1999, pp. 7-9.				
EXAMINER 			DATE CONSIDERED 04/02/05				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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<b>LIST OF ART CITED BY APPLICANT</b> <small>(Use several sheets if necessary)</small>				APPLICANT: Garo J. Derderian et al.			
				FILING DATE June 11, 2001		GROUP 2818	

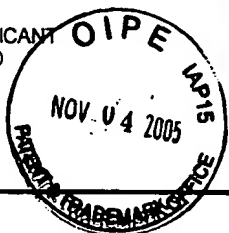


U.S. PATENT DOCUMENTS								
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
TL	AA	6,359,295 B2	03/2002	Lee et al.	—	—	/	
TL	AB	6,596,602 B2	07/2003	Lizuka et al.	—	—		
TL	AC	6,627,462 B1	09/2003	Yang et al.	—	—		
TL	AD	6,664,186 B1	12/2003	Callegari et al.	—	—		
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FOREIGN PATENT DOCUMENTS								
Examiner's Initials	Class	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
TL	AJ	KR 2002002157 A	05/2003	Lee, J.W.	—	—	—	—
TL	AK	EP 1 508 906 A2	02/2005	Lee et al.	—	—	—	—
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER		DATE CONSIDERED <i>Chul</i> 9/8/05						
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1748	SERIAL NO. 09/879,231
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Garo J. Derderian	
				FILING DATE June 11, 2001	GROUP 2818



U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
⌒	AA	6,824,816	11/2004	Aaltonen et al.			
⌒	AB	6,307,730	10/2001	Yamanishi			
⌒	AC	6,800,892	10/2004	Bhattacharyya			
⌒	AD	2003/0215960	11/2003	Mitsuhashi			
⌒	AE	2005/0082593 A1	04/2005	Lee et al.			
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FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
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EXAMINER <i>Thao</i>	DATE CONSIDERED 05/13/06
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DEC 05 2005

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1748	SERIAL NO. 09/879,231
<b>LIST OF ART CITED BY APPLICANT</b> <small>(Use several sheets if necessary)</small>				APPLICANT: Garo J. Derderian et al.	
				FILING DATE June 11, 2001	GROUP 2818

U.S. PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
TL	AA	5811344	09/1998	Tu et al.			
TL	AB	6596583	07/2003	Agarwal et al.			
TL	AC	6069053	05/2000	Ping et al.			
TL	AD	6033967	03/2000	Li et al.			
TL	AE	5885882	03/1999	Schugraf et al.			
TL	AF	6174770	01/2001	Chi, Min-hwa			
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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EXAMINER <i>Thacker</i>	DATE CONSIDERED 5/13/06
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Sheet 1 of 1

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Garo J. Dardarian et al.			
					FILING DATE June 11, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS								
Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate		
	AA	2002/0153579 A1	10/2002	Yamamoto				
	AB	2002/0182820 A1	12/2002	Choi et al.				
	AC	2002/0197744 A1	12/2002	Lee				
	AD	2004/0018747 A1	01/2004	Lee et al.				
	AE	2004/0125541 A1	07/2004	Chung				
	AF	6,849,505 B2	02/2005	Lee et al.				
	AG	6,946,342 B2	09/2005	Yeo et al.				
	AH							
FOREIGN PATENT DOCUMENTS								
Document Number	Date	Country	Class	Subclass	Translation			
					Yes	No		
	AJ	JP 2002/222934 A	08/2002	Japan	-	-	X	
	AK							
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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					FILING DATE June 11, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS								
Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
TL ↓	AA	6,207,561	03/2001	Hwang et al.				
	AB	5,006,956	04/1991	Kawakita et al.				
	AC	6,730,163	05/2004	Vaartstra				
	AD	6,809,212	10/2004	Meiere et al.				
	AE	6,881,260	04/2005	Marsh et al.				
	AF	7,018,469	03/2006	Li et al.				
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FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
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